



JPW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Satoshi INOUE et al.

Group Art Unit: 2812

Application No.: 10/748,206

Examiner: R. BOOTH

Filed: December 31, 2003

Docket No.: 040852.98

For: MANUFACTURING METHOD OF ACTIVE MATRIX SUBSTRATE , ACTIVE MATRIX
SUBSTRATE AND LIQUID CRYSTAL DISPLAY DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

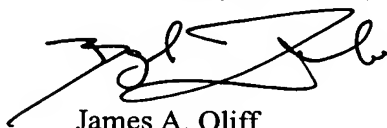
Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.



2. One or more reference cited herein was cited in a counterpart foreign application.
See Reference 1.

Respectfully submitted,



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Date: September 14, 2006

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Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. 10/748,206	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Satoshi INOUE et al.			
				FILING DATE December 31, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
	1.	Sameshima T., Laser beam application to the thin film transistors, Applied Surface Science, April 2, 1996 Vol. 96-98					
		Pages 352-358					
EXAMINER				DATE CONSIDERED			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: September 14, 2006